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### TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

# TC74ACT08P, TC74ACT08F, TC74ACT08FN, TC74ACT08FT

### QUAD 2-INPUT AND GATE

The TC74ACT08 is an advanced high speed CMOS 2-INPUT AND GATE fabricated with silicon gate and double - layer metal wiring C<sup>2</sup>MOS technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

This device may be used as a level converter for interfacing TTL or NMOS to High Speed CMOS. The inputs are compatible with TTL, NMOS and CMOS output voltage levels.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

### FEATURES:

- High Speed------t<sub>pd</sub> = 4.7ns(typ.) at  $V_{CC}$  = 5V
- Low Power Dissipation  $\dots I_{CC} = 4\mu A(Max.)$  at Ta = 25°C
- $\bullet$  Compatible with TTL outputs  $\cdots$   $V_{I\,L}$  = 0.8V (Max.)
  - V<sub>I H</sub> = 2.0V (Min.)

• Symmetrical Output Impedance…  $|I_{OH}| = I_{OL} = 24mA(Min.)$ Capability of driving 50 $\Omega$ 

transmission lines.

- Balanced Propagation Delays……  $t_{\text{pLH}} \!\simeq\! t_{\text{pHL}}$
- Pin and Function Compatible with 74F08

#### IEC LOGIC SYMBOL



(Note) The JEDEC SOP (FN) is not available in Japan.



#### **PIN ASSIGNMENT**



### TRUTH TABLE

А	В	Y
L	L	L
L	Н	L
н	L	L
Н	Н	Н

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### **ABSOLUTE MAXIMUM RATINGS**

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage Range	V <sub>cc</sub>	-0.5~7.0	V
DC Input Voltage	VIN	$-0.5 \sim V_{CC} + 0.5$	V
DC Output Voltage	V <sub>OUT</sub>	$-0.5 \sim V_{CC} + 0.5$	V
Input Diode Current	I <sub>1K</sub>	± 20	mA
Output Diode Current	Ι <sub>οκ</sub>	± 50	mA
DC Output Current	I <sub>OUT</sub>	± 50	mA
DC V <sub>CC</sub> /Ground Current	I <sub>cc</sub>	± 100	mA
Power Dissipation	P <sub>D</sub>	500 (DIP)* /180 (SOP/TSSOP)	mW
Storage Temperature	T <sub>stg</sub>	-65~150	°C

\*500mW in the range of Ta = - 40°C~65°C. From Ta = 65°C to 85°C a derating factor of - 10mW/°C should be applied up to 300mW.

### **RECOMMENDED OPERATING CONDITIONS**

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage	V <sub>cc</sub>	4.5~5.5	V
Input Voltage	VIN	0~V <sub>cc</sub>	V
Output Voltage	V <sub>OUT</sub>	0~V <sub>cc</sub>	V
Operating Temperature	T <sub>opr</sub>	-40~85	°C
Input Rise and Fall Time	dt/dV	0~10	ns / V

#### **DC ELECTRICAL CHARACTERISTICS**

PARAMETER	CVMADOL	TEST CONDITION		V <sub>cc</sub>	Ta = 25°C			Ta = −40~85°C		
PARAIVIETER	SYMBOL			(V)	MIN.	TYP.	MAX.	MIN.	MAX.	UNIT
High - Level Input Voltage	VIH				2.0	_	_	2.0	_	v
Low - Level Input Voltage	VIL			4.5 〈 5.5	-	_	0.8	_	0.8	<
High - Level Output Voltage	V <sub>OH</sub>	$V_{IN} = V_{IH}$	$I_{OH} = -50 \mu A$ $I_{OH} = -24 m A$ $I_{OH} = -75 m A^*$	4.5 4.5 5.5	4.4 3.94 —	4.5 		4.4 3.80 3.85		v
Low - Level Output Voltage	V <sub>OL</sub>	$ \begin{array}{c} V_{\rm IN} = & I_{\rm OL} = 50\mu A \\ V_{\rm IH}  or  V_{\rm IL} & I_{\rm OL} = 24mA \\ I_{\rm OL} = 75mA^* \end{array} $		4.5 4.5 5.5		0.0 	0.1 0.36 —		0.1 0.44 1.65	v
Input Leakage Current	I <sub>IN</sub>	$V_{IN} = V_{CC} \text{ or } GND$		5.5			±0.1	_	± 1.0	•
	I <sub>cc</sub>	$V_{IN} = V_{CC} \text{ or } GN$	5.5		-	4.0	-	40.0	μA	
Quiescent Supply Current	۱ <sub>с</sub>	PER INPUT : V <sub>II</sub> OTHER INPUT	5.5	_	_	1.35	_	1.5	mA	

\* : This spec indicates the capability of driving 50  $\!\Omega$  transmission lines.

One output should be tested at a time for a 10ms maximum duration.

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UNIT

	AC ELECTRICAL CHARACTERISTICS ( $C_L = 50 \text{ pr}$ , $R_L = 500 \Omega$ , input $t_r = t_f = 3 \text{ ns}$ )									
			TEST CONDITION		Ta = 25°C			Ta = -40~85°C		
PARAMETER	SYMBOL	V.	′ <sub>cc</sub> (V)	MIN.	TYP.	MAX.	MIN.	MAX.		

#### FUECTBICAL CHARACTERISTICS (C -1...... . . . 2----

Propagation Delay Time	t <sub>pLH</sub> t <sub>pHL</sub>		5.0±0.5	—	5.4	8.7	1.0	10.0	ns
Input Capacitance	C <sub>IN</sub>			-	5	10	—	10	'nE
Power Dissipation Capacitance	C <sub>PD</sub> (1)				21	—	_	1	pF
Note (1) $C_{PD}$ is defined as the value of the internal equivalent capacitance which is calculated from the									

(Τ) Ч operating current consumption.

Average operating current can be obtained by the equation:

 $I_{CC (opr.)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC} / 4 (per Gate)$ 

### DIP 14PIN OUTLINE DRAWING (DIP14-P-300-2.54)

Unit in mm



### SOP 14PIN (200mil BODY) OUTLINE DRAWING (SOP14-P-300-1.27)





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